

Dual N-Channel 30-V (D-S) MOSFET

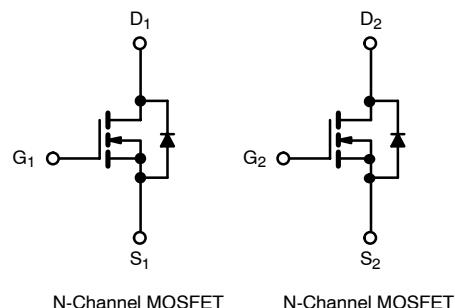
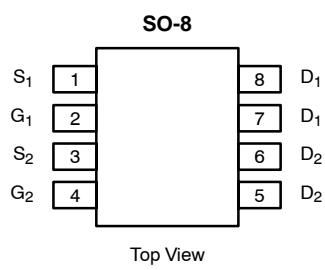
PRODUCT SUMMARY		
V _{DS} (V)	r _{DS(on)} (Ω)	I _D (A)
30	0.036 @ V _{GS} = 10 V	5.9
	0.053 @ V _{GS} = 4.5 V	4.9

FEATURES

- TrenchFET® Power MOSFET
- Lead (Pb)-Free Version is RoHS Compliant



Available



Ordering Information: Si4936ADY-T1
Si4936ADY-T1—E3 (Lead (Pb)-Free)

ABSOLUTE MAXIMUM RATINGS (T_A = 25°C UNLESS OTHERWISE NOTED)

Parameter	Symbol	10 secs	Steady State	Unit
Drain-Source Voltage	V _{DS}	30		V
Gate-Source Voltage	V _{GS}		±20	
Continuous Drain Current (T _J = 150°C) ^a	T _A = 25°C	I _D	5.9	A
	T _A = 70°C		4.7	
Pulsed Drain Current	I _{DM}	±30		A
Continuous Source Current (Diode Conduction) ^a	I _S	1.7	0.9	
Maximum Power Dissipation ^a	T _A = 25°C	P _D	2.0	W
	T _A = 70°C		1.3	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	−55 to 150		°C

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^a	t ≤ 10 sec	R _{thJA}	50	°C/W
	Steady State		90	
Maximum Junction-to-Foot (Drain)	R _{thJF}	32	40	

Notes

a. Surface Mounted on 1" x 1" FR4 Board.

SPECIFICATIONS ($T_J = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	1.0		3.0	V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$		1	μA	
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$		5		
On-State Drain Current ^a	$I_{D(\text{on})}$	$V_{DS} \geq 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			A
Drain-Source On-State Resistance ^a	$r_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 5.9 \text{ A}$		0.032	0.036	Ω
		$V_{GS} = 4.5 \text{ V}, I_D = 4.9 \text{ A}$		0.042	0.053	
Forward Transconductance ^a	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 5.9 \text{ A}$	15			S
Diode Forward Voltage ^a	V_{SD}	$I_S = 1.7 \text{ A}, V_{GS} = 0 \text{ V}$		0.8	1.2	V
Dynamic^b						
Total Gate Charge	Q_g	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 5.9 \text{ A}$		13	20	nC
Gate-Source Charge	Q_{gs}			2.3		
Gate-Drain Charge	Q_{gd}			2.0		
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = 15 \text{ V}, R_L = 15 \Omega$ $I_D \approx 1 \text{ A}, V_{GEN} = 10 \text{ V}, R_G = 6 \Omega$		6	12	ns
Rise Time	t_r			14	25	
Turn-Off Delay Time	$t_{d(\text{off})}$			30	60	
Fall Time	t_f			5	10	
Source-Drain Reverse Recovery Time	t_{rr}		$I_F = 1.7 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$	30	60	

Notes

- a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)